Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/668,357	TAKAHASHI ET AL.
Examiner	Art Unit
Eric Chang	2116

SEARCHED						
Class	Subclass	Date Examine				
713	401	7/28/2005	EC			
706	13	7/28/2005	EC			
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INTERFERENCE SEARCHED					
Class	Subclass	Date Examin			
713	401	7/27/2005	EC		
706	13	7/27/2005	EC		
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SEARCI (INCLUDING SEA	H NOTE ARCH S	S TRATEGY)
		DATE	EXMR
EAST USPAT/PGPUB EPO/JPO		7/28/2005	EC
Consulted Examiner James Trujillo		8/4/2005	EC
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